TOSHIBA Field Effect Transistor Silicon N/P Channel MOS Type

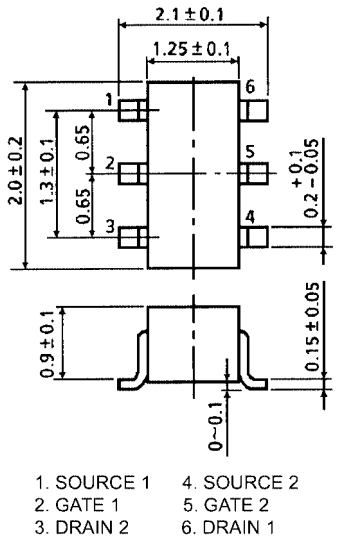
SSM6L09FU

Power Management Switch

High Speed Switching Applications

- Small package
- Low on resistance Q1: R_{on} = 0.7 Ω (max) (@V_{GS} = 10 V)
  Q2: R_{on} = 2.7 Ω (max) (@V_{GS} = −10 V)

Unit: mm



1. SOURCE 1 4. SOURCE 2
2. GATE 1 5. GATE 2
3. DRAIN 2 6. DRAIN 1

US6

JEDEC	—
JEITA	—
TOSHIBA	2-2J1C

Weight: 6.8 mg (typ.)

Q1 Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-Source voltage		V_{DS}	30	V
Gate-Source voltage		V_{GSS}	±20	V
Drain current	DC	I_D	400	mA
	Pulse	I_{DP}	800	

Q2 Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-Source voltage		V_{DS}	−30	V
Gate-Source voltage		V_{GSS}	±20	V
Drain current	DC	I_D	−200	mA
	Pulse	I_{DP}	−400	

Maximum Ratings (Q1, Q2 common) (Ta = 25°C)

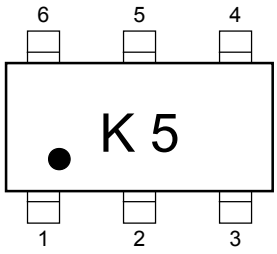
Characteristics	Symbol	Rating	Unit
Drain power dissipation (Ta = 25°C)	P_D (Note1)	300	mW
Channel temperature	T_{ch}	150	°C
Storage temperature range	T_{stg}	−55~150	°C

Note1: Total rating, mounted on FR4 board
(25.4 mm × 25.4 mm × 1.6 t, Cu Pad: 0.32 mm^2 × 6) Figure 1.

Handling Precaution

When handling individual devices (which are not yet mounting on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

Marking



Equivalent Circuit (top view)

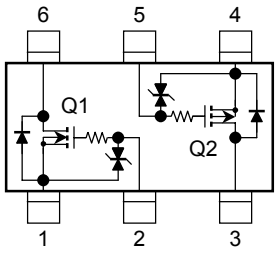
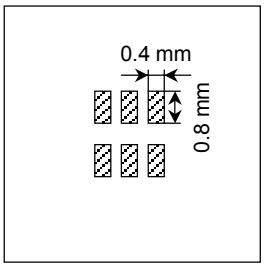


Figure 1: 25.4 mm × 25.4 mm × 1.6 t, Cu Pad: 0.32 mm² × 6



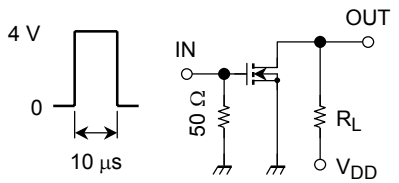
Q1 Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	V_{GS} = ±16 V, V_{DS} = 0	—	—	±1	μA
Drain-Source breakdown voltage		$V_{(BR)\ DSS}$	I_D = 1 mA, V_{GS} = 0	30	—	—	V
Drain cut-off current		I_{DSS}	V_{DS} = 20 V, V_{GS} = 0	—	—	1	μA
Gate threshold voltage		V_{th}	V_{DS} = 5 V, I_D = 0.1 mA	1.1	—	1.8	V
Forward transfer admittance		$\|Y_{fs}\|$	V_{DS} = 5 V, I_D = 200 mA (Note2)	270	—	—	mS
Drain-Source ON resistance		$R_{DS\ (ON)}$	I_D = 200 mA, V_{GS} = 10 V (Note2)	—	0.53	0.7	Ω
			I_D = 200 mA, V_{GS} = 4 V (Note2)	—	0.8	1.2	
			I_D = 200 mA, V_{GS} = 3.3 V (Note2)	—	1.0	1.7	
Input capacitance		C_{iss}	V_{DS} = 5 V, V_{GS} = 0, f = 1 MHz	—	20	—	pF
Reverse transfer capacitance		C_{rss}		—	7	—	pF
Output capacitance		C_{oss}		—	16	—	pF
Switching time	Turn-on time	t_{on}	V_{DD} = 5 V, I_D = 200 mA,	—	72	—	ns
	Turn-off time	t_{off}	V_{GS} = 0~4 V	—	68	—	

Note2: Pulse test

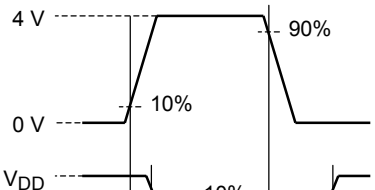
Switching Time Test Circuit (Q1: Nch MOS FET)

(a) Test circuit

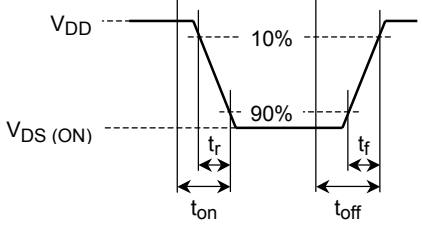


V_{DD} = 5 V
Duty ≦ 1%
V_{IN}: t_r, t_f < 5 ns
(Z_{out} = 50 Ω)
Common Source
Ta = 25°C

(b) V_{IN}



(c) V_{OUT}



Precaution

V_{th} can be expressed as voltage between gate and source when low operating current value is I_D = 100 μA for this product. For normal switching operation, $V_{GS\ (on)}$ requires higher voltage than V_{th} and $V_{GS\ (off)}$ requires lower voltage than V_{th}. (Relationship can be established as follows: $V_{GS\ (off)} < V_{th} < V_{GS\ (on)}$)

Please take this into consideration for using the device. V_{GS} recommended voltage of 4 V or higher to turn on this product.

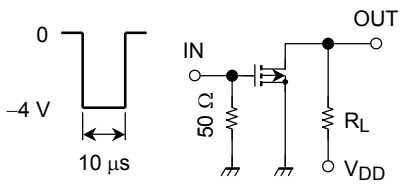
Q2 Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	V_{GS} = ±16 V, V_{DS} = 0	—	—	±1	μA
Drain-Source breakdown voltage		$V_{(BR)\ DSS}$	I_D = −1 mA, V_{GS} = 0	−30	—	—	V
Drain cut-off current		I_{DSS}	V_{DS} = −30 V, V_{GS} = 0	—	—	−1	μA
Gate threshold voltage		V_{th}	V_{DS} = −5 V, I_D = −0.1 mA	−1.1	—	−1.8	V
Forward transfer admittance		$\|Y_{fs}\|$	V_{DS} = −5 V, I_D = −100 mA (Note2)	115	—	—	mS
Drain-Source ON resistance		$R_{DS\ (ON)}$	I_D = −100 mA, V_{GS} = −10 V (Note2)	—	2.1	2.7	Ω
			I_D = −100 mA, V_{GS} = −4 V (Note2)	—	3.3	4.2	
			I_D = −100 mA, V_{GS} = −3.3 V(Note2)	—	4.0	6.0	
Input capacitance		C_{iss}	V_{DS} = −5 V, V_{GS} = 0, f = 1 MHz	—	22	—	pF
Reverse transfer capacitance		C_{rss}	V_{DS} = −5 V, V_{GS} = 0, f = 1 MHz	—	5	—	pF
Output capacitance		C_{oss}	V_{DS} = −5 V, V_{GS} = 0, f = 1 MHz	—	14	—	pF
Switching time	Turn-on time	t_{on}	V_{DD} = −5 V, I_D = −100 mA,	—	85	—	ns
	Turn-off time	t_{off}	V_{GS} = 0~−4 V	—	85	—	

Note2: Pulse test

Switching Time Test Circuit (Q2: Pch MOS FET)

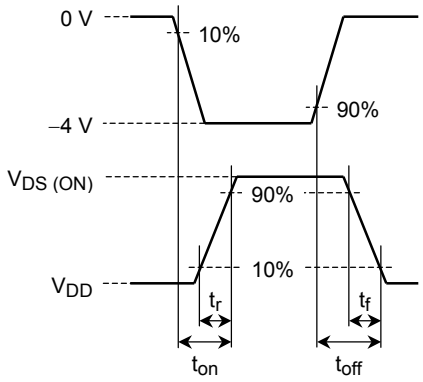
(a) Test circuit



V_{DD} = −5 V
Duty ≦ 1%
V_{IN}: t_r, t_f < 5 ns
(Z_{out} = 50 Ω)
Common Source
Ta = 25°C

(b) V_{IN}

(c) V_{OUT}



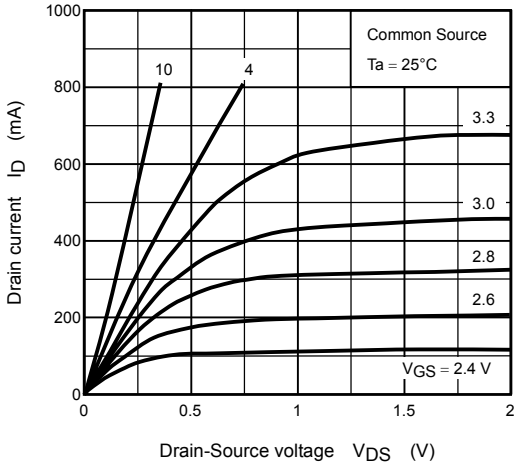
Precaution

V_{th} can be expressed as voltage between gate and source when low operating current value is I_D = −100 μA for this product. For normal switching operation, $V_{GS\ (on)}$ requires higher voltage than V_{th} and $V_{GS\ (off)}$ requires lower voltage than V_{th}. (Relationship can be established as follows: $V_{GS\ (off)} < V_{th} < V_{GS\ (on)}$)

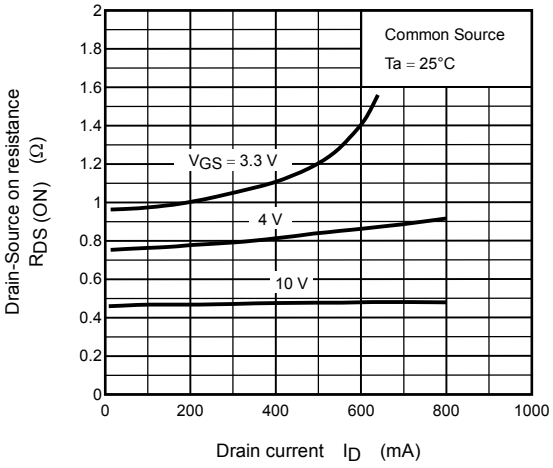
Please take this into consideration for using the device. V_{GS} recommended voltage of −4 V or higher to turn on this product.

Q1 (Nch MOS FET)

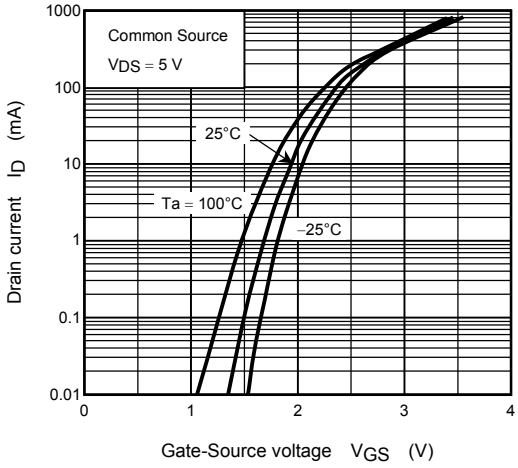
$I_D - V_{DS}$



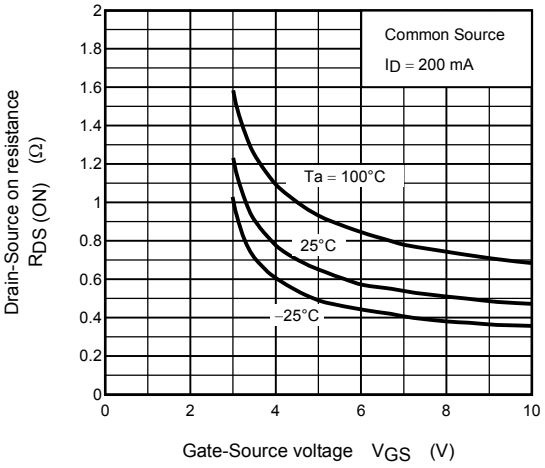
$R_{DS\ (ON)} - I_D$



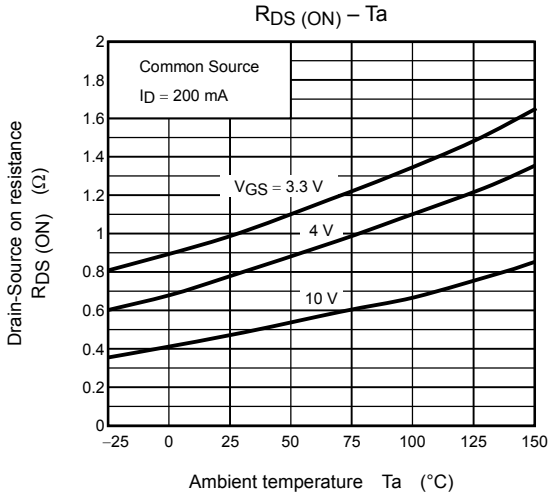
$I_D - V_{GS}$



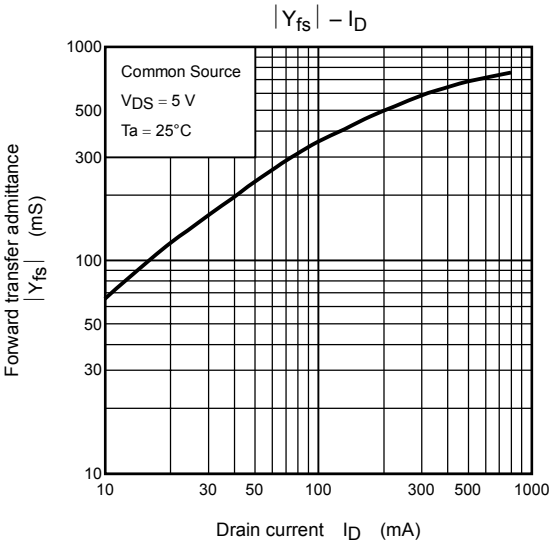
$R_{DS\ (ON)} - V_{GS}$



$R_{DS\ (ON)} - Ta$

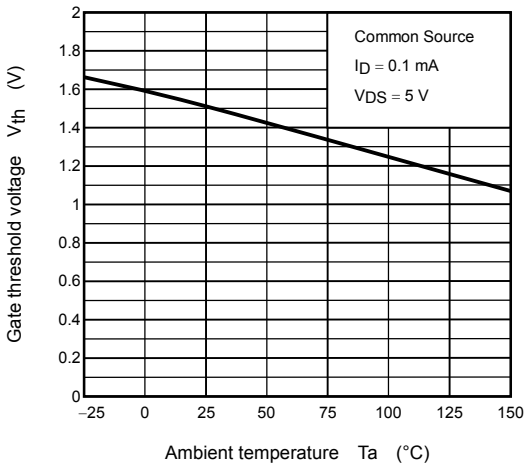


$|Y_{fs}| - I_D$

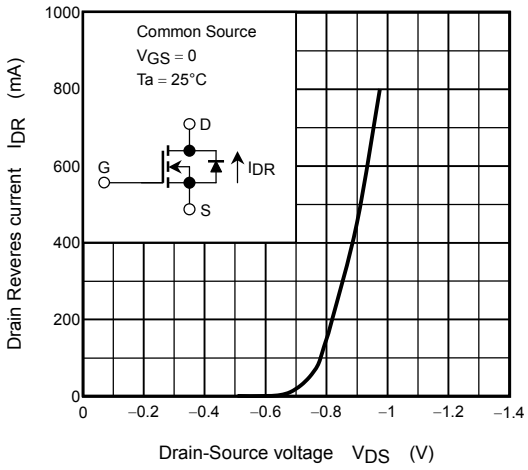


Q1 (Nch MOS FET)

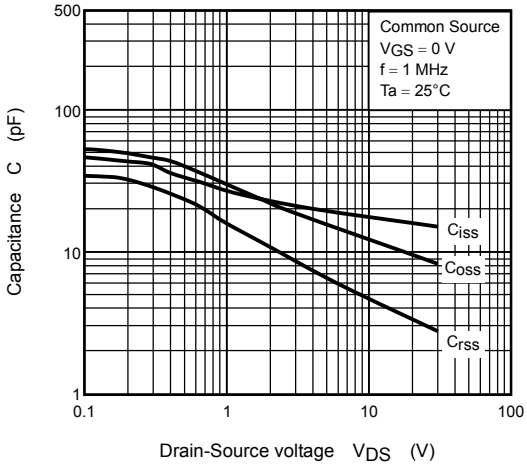
V_{th} – Ta



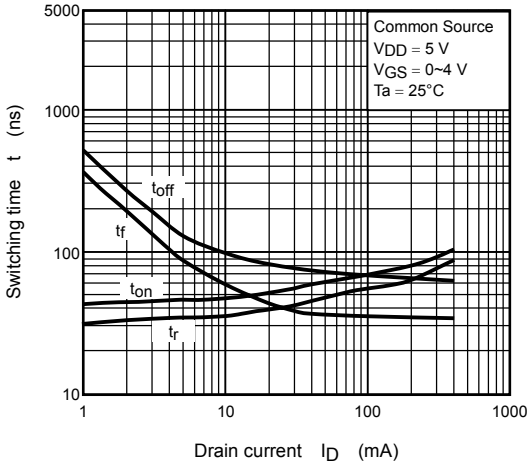
I_{DR} – V_{DS}



C – V_{DS}

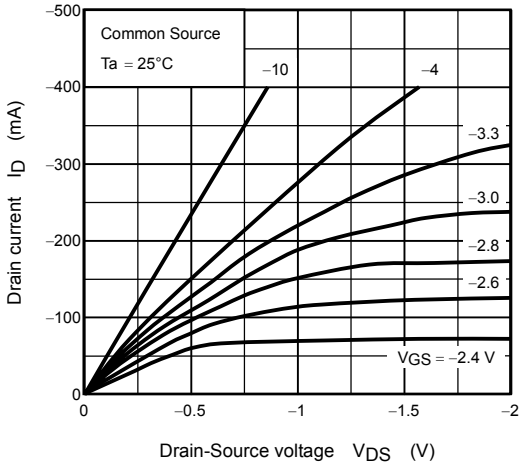


t – I_D

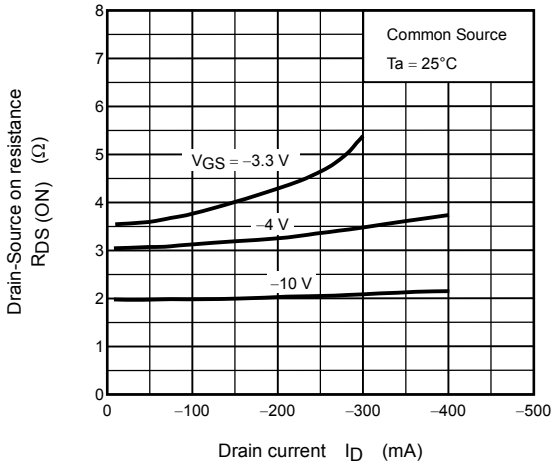


Q2 (Pch MOS FET)

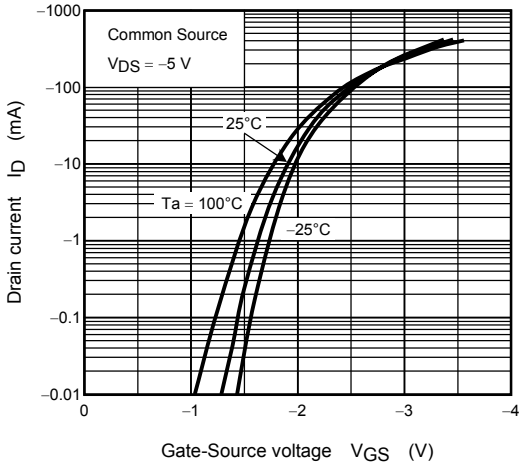
$I_D - V_{DS}$



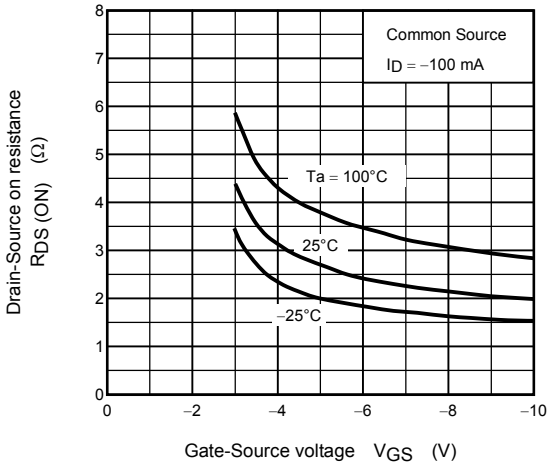
$R_{DS\ (ON)} - I_D$



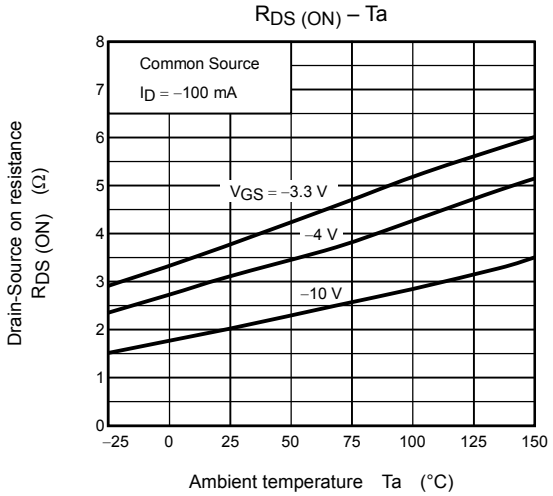
$I_D - V_{GS}$



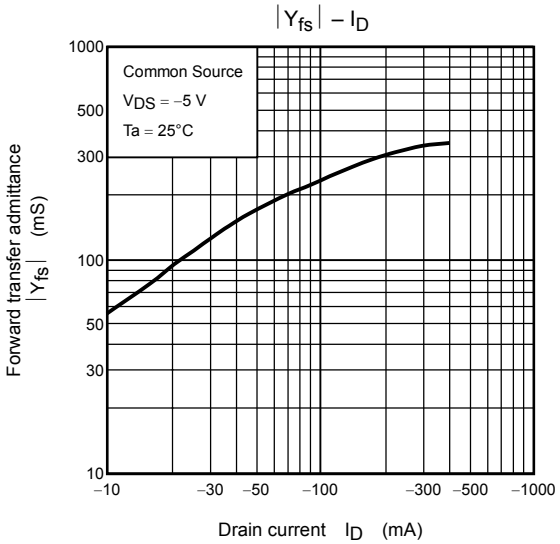
$R_{DS\ (ON)} - V_{GS}$



$R_{DS\ (ON)} - Ta$

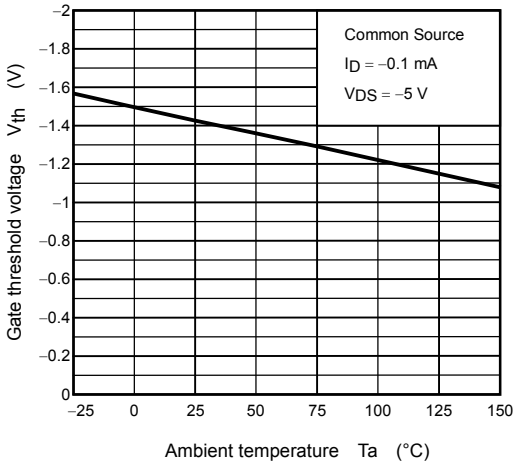


$|Y_{fs}| - I_D$

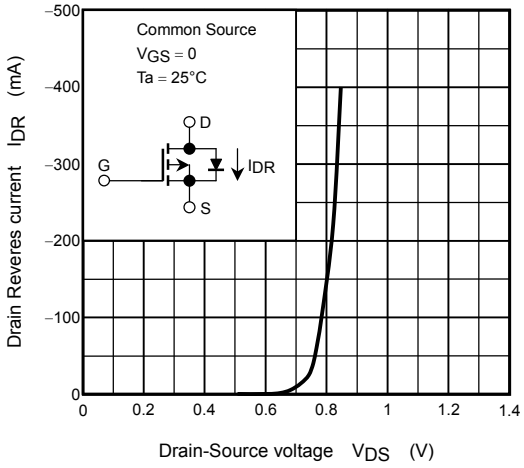


Q2 (Pch MOS FET)

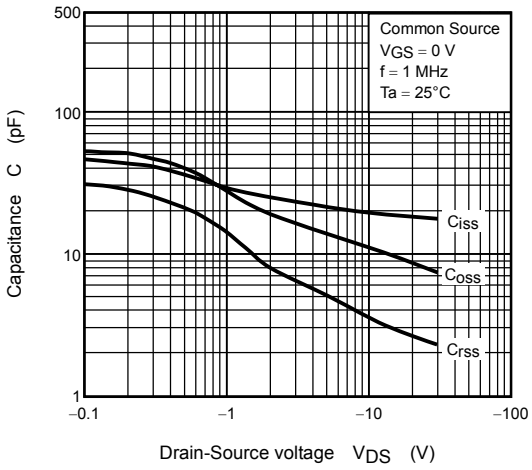
V_{th} – Ta



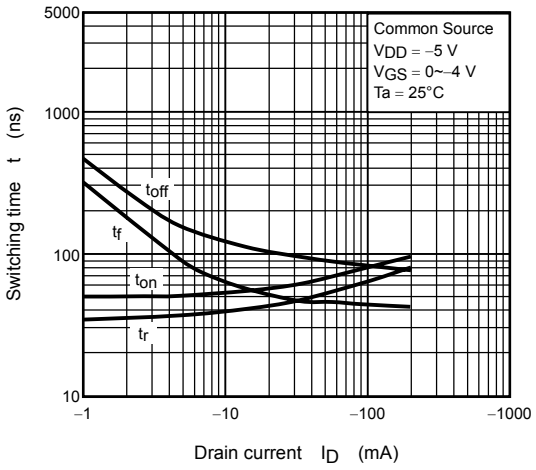
I_{DR} – V_{DS}



C – V_{DS}

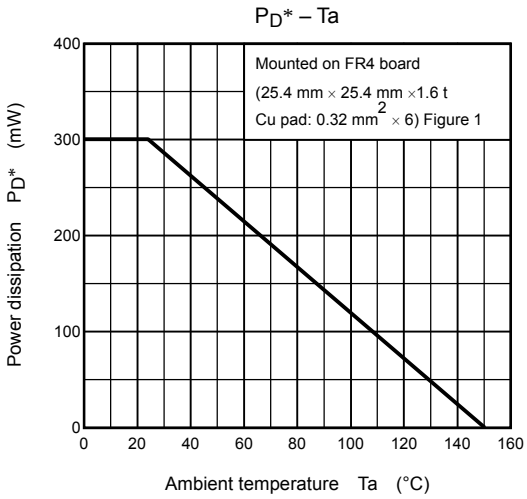


t – I_D



Q1, Q2 common

P_D* – Ta



*: Total rating

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